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	_	5,670,798	9-23-97	Schetzii			<u> </u>	11	ļ		
44		5,679,965	10-21-97	Schetzii	na		V		 	<u></u>	
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M		6,008,126	12-28-99	Leedy			1		
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		6,165,383	12-26-00	Chou						
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